



## 3.3V CMOS DUAL NEGATIVE-EDGE-TRIGGERED J-K FLIP-FLOP WITH CLEAR AND PRESET, 5 VOLT TOLERANT I/O

IDT74LVC112A

### FEATURES:

- 0.5 MICRON CMOS Technology
- ESD > 2000V per MIL-STD-883, Method 3015;  
> 200V using machine model (C = 200pF, R = 0)
- 1.27mm pitch SOIC, 0.635mm pitch QSOP,  
0.65mm pitch SSOP, 0.65mm pitch TSSOP packages
- Extended commercial range of -40°C to +85°C
- V<sub>CC</sub> = 3.3V ±0.3V, Normal Range
- V<sub>CC</sub> = 2.3V to 3.6V, Extended Range
- CMOS power levels (0.4μW typ. static)
- Rail-to-Rail output swing for increased noise margin
- All inputs, outputs and I/O are 5 Volt tolerant
- Supports hot insertion

### Drive Features for LVC112A:

- High Output Drivers: ±24mA
- Reduced system switching noise

### APPLICATIONS:

- 5V and 3.3V mixed voltage systems
- Data communication and telecommunication systems

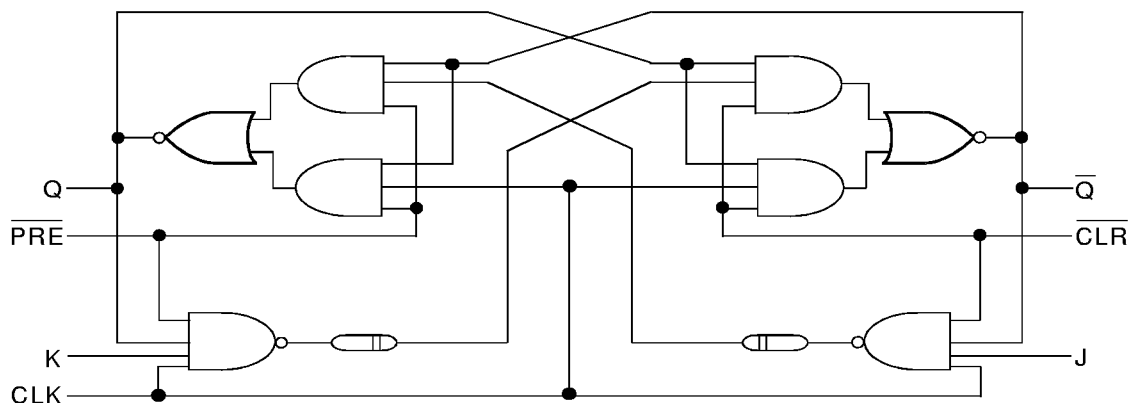
### DESCRIPTION:

This dual negative-edge-triggered J-K flip-flop is built using advanced dual metal CMOS technology. A low level at the preset ( $\overline{PRE}$ ) or clear ( $\overline{CLR}$ ) inputs sets or resets the outputs, regardless of the levels of the other inputs. When  $\overline{PRE}$  and  $\overline{CLR}$  are inactive (high), data at the J and K inputs meeting the setup time requirements is transferred to the outputs on the negative-going edge of the clock pulse. Clock triggering occurs at a voltage level and is not directly related to the rise time of the clock pulse. Following the hold-time interval, data at the J and K inputs can be changed without affecting the levels at the outputs. The LVC112A can perform as a toggle flip-flop by tying J and K high.

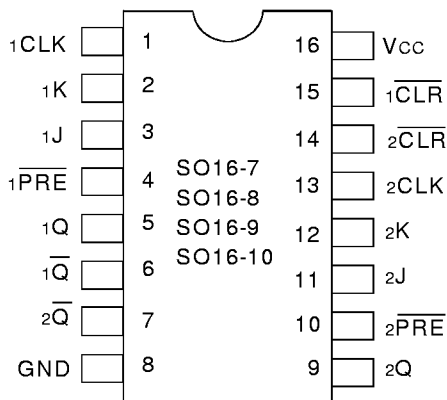
Inputs can be driven from either 3.3V or 5V devices. This feature allows the use of this device as a translator in a mixed 3.3V/5V supply system.

The LVC112A has been designed with a ±24mA output driver. This driver is capable of driving a moderate to heavy load while maintaining speed performance.

### Functional Block Diagram



## PIN CONFIGURATION



QSOP/ SOIC/ SSOP/ TSSOP  
TOP VIEW

## PIN DESCRIPTION

Pin Names	Description
xCLK	CLK Inputs
x $\overline{\text{CLR}}$	Clear Inputs (Active LOW)
x $\overline{\text{PRE}}$	Preset Inputs (Active LOW)
xJ, xK	Data Inputs
xQ, x $\overline{\text{Q}}$	Data Outputs

## FUNCTION TABLE (1)

Inputs					Outputs	
x $\overline{\text{PRE}}$	x $\overline{\text{CLR}}$	xCLK	xJ	xK	xQ	x $\overline{\text{Q}}$
L	H	X	X	X	H	L
H	L	X	X	X	L	H
L	L	X	X	X	H <sup>(2)</sup>	H <sup>(2)</sup>
H	H	↓	L	L	Q <sub>0</sub>	$\overline{\text{Q}}_0$
H	H	↓	H	L	H	L
H	H	↓	L	H	L	H
H	H	↓	H	H	Toggle	
H	H	H	X	X	Q <sub>0</sub>	$\overline{\text{Q}}_0$

### NOTES:

- H = HIGH Voltage Level  
L = LOW Voltage Level  
X = Don't Care  
Q<sub>0</sub> = Level of Q before the indicated steady-state input conditions were established.  
 $\overline{\text{Q}}_0$  = Complement of Q<sub>0</sub> or level of  $\overline{\text{Q}}$  before the indicated steady-state input conditions were established.
- The output levels in this configuration may not meet the minimum levels for VOH. Furthermore, this configuration is unstable; that is, it does not persist when either PRE or  $\overline{\text{CLR}}$  returns to its inactive (high) level.

## ABSOLUTE MAXIMUM RATINGS (1)

Symbol	Description	Max.	Unit
V <sub>TERM</sub> <sup>(2)</sup>	Terminal Voltage with Respect to GND	-0.5 to +6.5	V
V <sub>TERM</sub> <sup>(3)</sup>	Terminal Voltage with Respect to GND	-0.5 to +6.5	V
T <sub>STG</sub>	Storage Temperature	-65 to +150	°C
I <sub>OUT</sub>	DC Output Current	-50 to +50	mA
I <sub>IK</sub>	Continuous Clamp Current, V <sub>I</sub> < 0 or V <sub>O</sub> < 0	-50	mA
I <sub>CC</sub>	Continuous Current through each V <sub>CC</sub> or GND	±100	mA

LVC QUAD Link

### NOTES:

- Stresses greater than those listed under ABSOLUTE MAXIMUM RATINGS may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.
- V<sub>CC</sub> terminals.
- All terminals except V<sub>CC</sub>.

## CAPACITANCE (T<sub>A</sub> = +25°C, f = 1.0MHz)

Symbol	Parameter <sup>(1)</sup>	Conditions	Typ.	Max.	Unit
C <sub>IN</sub>	Input Capacitance	V <sub>IN</sub> = 0V	4.5	6	pF
C <sub>OUT</sub>	Output Capacitance	V <sub>OUT</sub> = 0V	5.5	8	pF
C <sub>I/O</sub>	I/O Port Capacitance	V <sub>IN</sub> = 0V	6.5	8	pF

LVC QUAD Link

### NOTE:

- As applicable to the device type.

**DC ELECTRICAL CHARACTERISTICS OVER OPERATING RANGE**

Following Conditions Apply Unless Otherwise Specified:

Operating Condition:  $T_A = -40^\circ\text{C}$  to  $+85^\circ\text{C}$ 

Symbol	Parameter	Test Conditions		Min.	Typ. <sup>(1)</sup>	Max.	Unit
V <sub>IH</sub>	Input HIGH Voltage Level	V <sub>CC</sub> = 2.3V to 2.7V		1.7	—	—	V
		V <sub>CC</sub> = 2.7V to 3.6V		2	—	—	
V <sub>IL</sub>	Input LOW Voltage Level	V <sub>CC</sub> = 2.3V to 2.7V		—	—	0.7	V
		V <sub>CC</sub> = 2.7V to 3.6V		—	—	0.8	
I <sub>IH</sub> I <sub>IL</sub>	Input Leakage Current	V <sub>CC</sub> = 3.6V	V <sub>I</sub> = 0 to 5.5V	—	—	±5	μA
I <sub>OZH</sub> I <sub>OZL</sub>	High Impedance Output Current (3-State Output pins)	V <sub>CC</sub> = 3.6V	V <sub>O</sub> = 0 to 5.5V	—	—	±10	μA
I <sub>OFF</sub>	Input/Output Power Off Leakage	V <sub>CC</sub> = 0V, V <sub>IN</sub> or V <sub>O</sub> ≤ 5.5V		—	—	±50	μA
V <sub>IK</sub>	Clamp Diode Voltage	V <sub>CC</sub> = 2.3V, I <sub>IN</sub> = -18mA		—	-0.7	-1.2	V
V <sub>H</sub>	Input Hysteresis	V <sub>CC</sub> = 3.3V		—	100	—	mV
I <sub>CC1</sub> I <sub>CC2</sub> I <sub>CC3</sub>	Quiescent Power Supply Current	V <sub>CC</sub> = 3.6V	V <sub>IN</sub> = GND or V <sub>CC</sub>	—	—	10	μA
ΔI <sub>CC</sub>	Quiescent Power Supply Current Variation	One input at V <sub>CC</sub> - 0.6V other inputs at V <sub>CC</sub> or GND		—	—	500	μA

LVC QUAD Link

**NOTE:**1. Typical values are at V<sub>CC</sub> = 3.3V, +25°C ambient.**OUTPUT DRIVE CHARACTERISTICS**

Symbol	Parameter	Test Conditions <sup>(1)</sup>		Min.	Max.	Unit
V <sub>OH</sub>	Output HIGH Voltage	V <sub>CC</sub> = 2.3V to 3.6V	I <sub>OH</sub> = -0.1mA	V <sub>CC</sub> - 0.2	—	V
		V <sub>CC</sub> = 2.3V	I <sub>OH</sub> = -6mA	2	—	
		V <sub>CC</sub> = 2.3V	I <sub>OH</sub> = -12mA	1.7	—	
		V <sub>CC</sub> = 2.7V		2.2	—	
		V <sub>CC</sub> = 3.0V		2.4	—	
		V <sub>CC</sub> = 3.0V	I <sub>OH</sub> = -24mA	2.2	—	
V <sub>OL</sub>	Output LOW Voltage	V <sub>CC</sub> = 2.3V to 3.6V	I <sub>OL</sub> = 0.1mA	—	0.2	V
		V <sub>CC</sub> = 2.3V	I <sub>OL</sub> = 6mA	—	0.4	
			I <sub>OL</sub> = 12mA	—	0.7	
		V <sub>CC</sub> = 2.7V	I <sub>OL</sub> = 12mA	—	0.4	
		V <sub>CC</sub> = 3.0V	I <sub>OL</sub> = 24mA	—	0.55	

LVC QUAD Link

**NOTE:**1. V<sub>IH</sub> and V<sub>IL</sub> must be within the min. or max. range shown in the DC ELECTRICAL CHARACTERISTICS OVER OPERATING RANGE table for the appropriate V<sub>CC</sub> range. T<sub>A</sub> = -40°C to +85°C.

**OPERATING CHARACTERISTICS,  $T_A = 25^\circ\text{C}$** 

Symbol	Parameter	Test Conditions	Vcc = 2.5V±0.2V	Vcc = 3.3V±0.3V	Unit
			Typical	Typical	
CPD	Power Dissipation Capacitance per Flip-Flop	CL = 0pF, f = 10Mhz	—	24	pF

**SWITCHING CHARACTERISTICS (1)**

Symbol	Parameter	Vcc = 2.5V±0.2V		Vcc = 2.7V		Vcc = 3.3V±0.3V		Unit
		Min.	Max.	Min.	Max.	Min.	Max.	
fMAX		—	—	150	—	150	—	MHz
tPLH tPHL	Propagation Delay x $\overline{\text{CLR}}$ or $\overline{\text{PRE}}$ to xQ or x $\overline{\text{Q}}$	—	—	—	5.5	1	4.8	ns
tPLH tPHL	Propagation Delay x $\overline{\text{CLK}}$ to xQ or x $\overline{\text{Q}}$	—	—	—	7.1	1	5.9	ns
tsu	Setup Time, Data before CLK $\downarrow$	—	—	2.3	—	3.1	—	ns
tsu	Setup Time, $\overline{\text{PRE}}$ or $\overline{\text{CLR}}$ inactive	—	—	1.1	—	2.4	—	ns
tH	Hold Time, data after CLK $\downarrow$	—	—	0.7	—	2.5	—	ns
tW	Pulse Width, CLK HIGH or LOW	—	—	3.3	—	3.3	—	ns
tSK(0)	Output Skew(2)	—	—	—	—	—	500	ps

**NOTES:**

1. See test circuits and waveforms.  $T_A = -40^\circ\text{C}$  to  $+85^\circ\text{C}$ .
2. Skew between any two outputs of the same package and switching in the same direction.

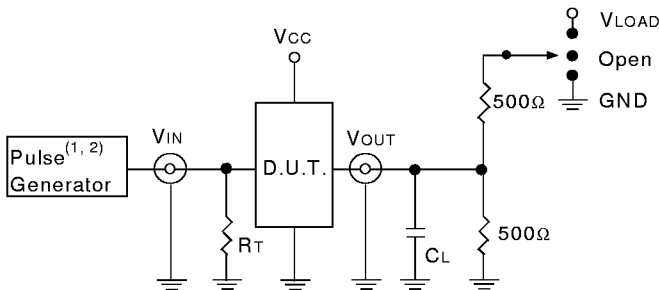
**TEST CIRCUITS AND WAVEFORMS**

**TEST CONDITIONS**

Symbol	V <sub>CC</sub> (1)= 2.5V ±0.2V	V <sub>CC</sub> (2)= 3.3V ±0.3V & 2.7V	Unit
V <sub>LOAD</sub>	2 x V <sub>CC</sub>	6	V
V <sub>IH</sub>	V <sub>CC</sub>	2.7	V
V <sub>T</sub>	V <sub>CC</sub> / 2	1.5	V
V <sub>LZ</sub>	150	300	mV
V <sub>HZ</sub>	150	300	mV
C <sub>L</sub>	30	50	pF

LVC QUAD Link

**TEST CIRCUITS FOR ALL OUTPUTS**



LVC QUAD Link

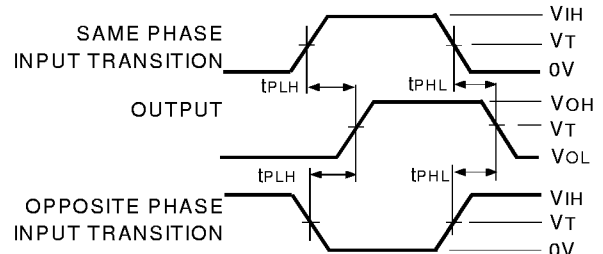
**DEFINITIONS:**

C<sub>L</sub> = Load capacitance: includes jig and probe capacitance.  
 R<sub>T</sub> = Termination resistance: should be equal to Z<sub>OUT</sub> of the Pulse Generator.

**NOTES:**

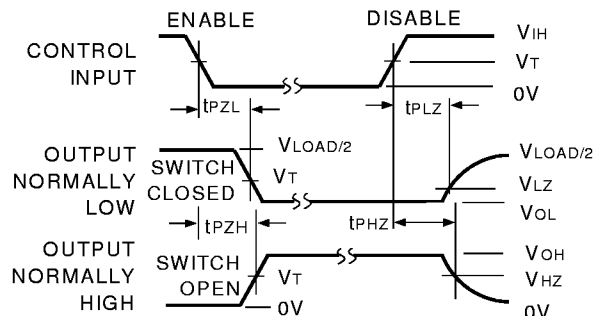
1. Pulse Generator for All Pulses: Rate ≤ 10MHz; t<sub>F</sub> ≤ 2ns; t<sub>R</sub> ≤ 2ns.
2. Pulse Generator for All Pulses: Rate ≤ 10MHz; t<sub>F</sub> ≤ 2.5ns; t<sub>R</sub> ≤ 2.5ns.

**PROPAGATION DELAY**



LVC QUAD Link

**ENABLE AND DISABLE TIMES**



LVC QUAD Link

**NOTE:**

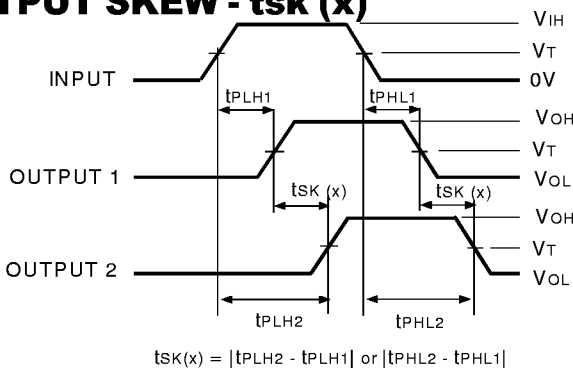
1. Diagram shown for input Control Enable-LOW and input Control Disable-HIGH.

**SWITCH POSITION**

Test	Switch
Open Drain Disable Low Enable Low	V <sub>LOAD</sub>
Disable High Enable High	GND
All Other tests	Open

LVC QUAD Link

**OUTPUT SKEW - t<sub>SK</sub>(x)**



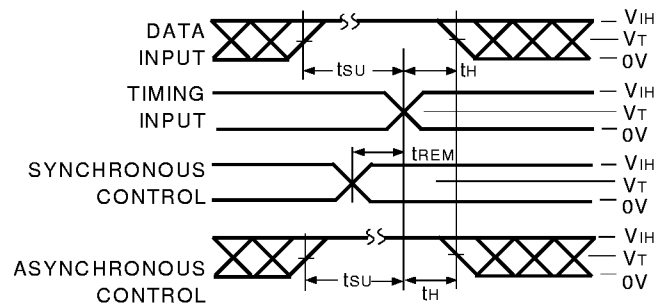
$$t_{SK}(x) = |t_{PLH2} - t_{PLH1}| \text{ or } |t_{PHL2} - t_{PHL1}|$$

LVC QUAD Link

**NOTES:**

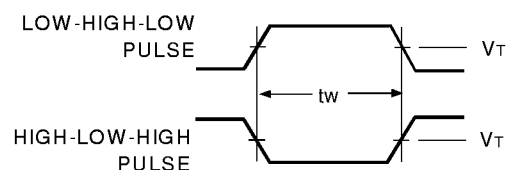
1. For t<sub>SK</sub>(a) OUTPUT1 and OUTPUT2 are any two outputs.
2. For t<sub>SK</sub>(b) OUTPUT1 and OUTPUT2 are in the same bank.

**SET-UP, HOLD, AND RELEASE TIMES**



LVC QUAD Link

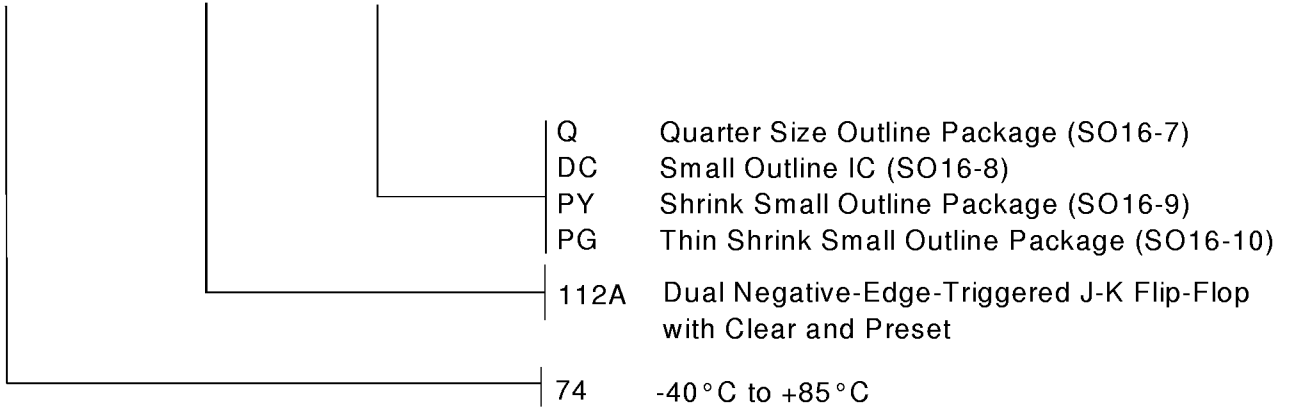
**PULSE WIDTH**



LVC QUAD Link

## ORDERING INFORMATION

IDT XX LVC XXXX XX  
Temp. Range Device Type Package



**CORPORATE HEADQUARTERS**  
2975 Stender Way  
Santa Clara, CA 95054

**for SALES:**  
800-345-7015 or 408-727-6116  
fax: 408-492-8674  
[www.idt.com](http://www.idt.com)\*

\*To search for sales office near you, please click the sales button found on our home page or dial the 800# above and press 2.  
The IDT logo is a registered trademark of Integrated Device Technology, Inc.